United States Patent [19]

Gross

[11] **Patent Number: Des. 311,346**

[45] **Date of Patent: ** Oct. 16, 1990**

[54] **ELECTRONIC TEST PROBE**

[75] Inventor: **Robert F. Gross**, Andover, Mass.

[73] Assignee: **Q.A. Technology Company**, Exeter, N.H.

[**] Term: **14 Years**

[21] Appl. No.: **101,169**

[22] Filed: **Sep. 25, 1987**

[52] **U.S. Cl.** **D10/80**

[58] **Field of Search** .... D10/75-80; 324/158 P

[56] **References Cited**

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[57] **CLAIM**

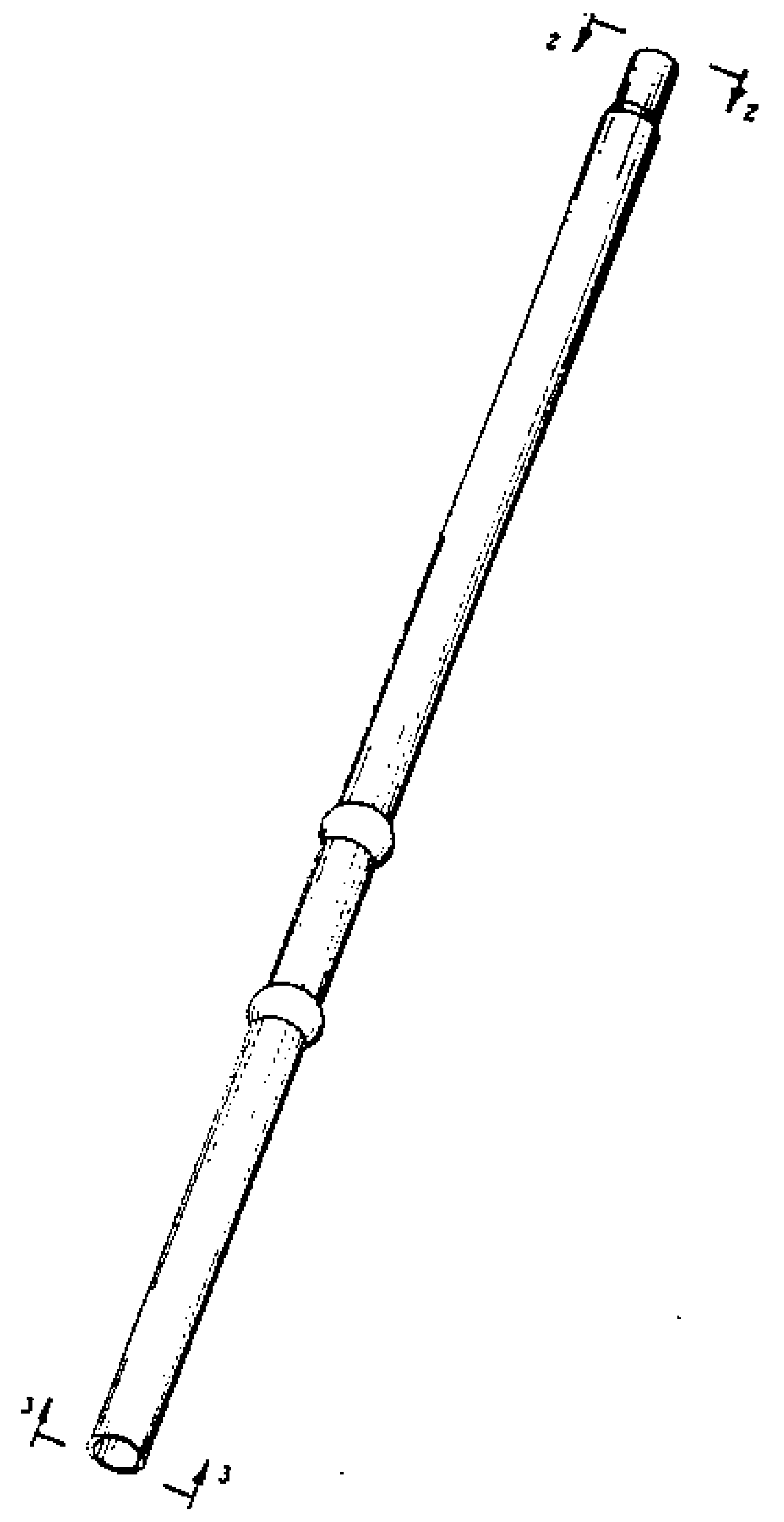
The ornamental design for electronic test probe, as shown and described.

DESCRIPTION

FIG. 1 is a front perspective view of a electronic test probe showing my new design;

FIG. 2 is a rear elevational view, taken along line 2—2 of FIG. 1; and

FIG. 3 is a front end elevational view thereof, taken along line 3—3 of FIG. 3.



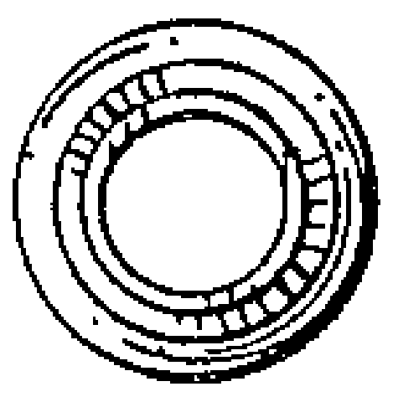


FIG. 2

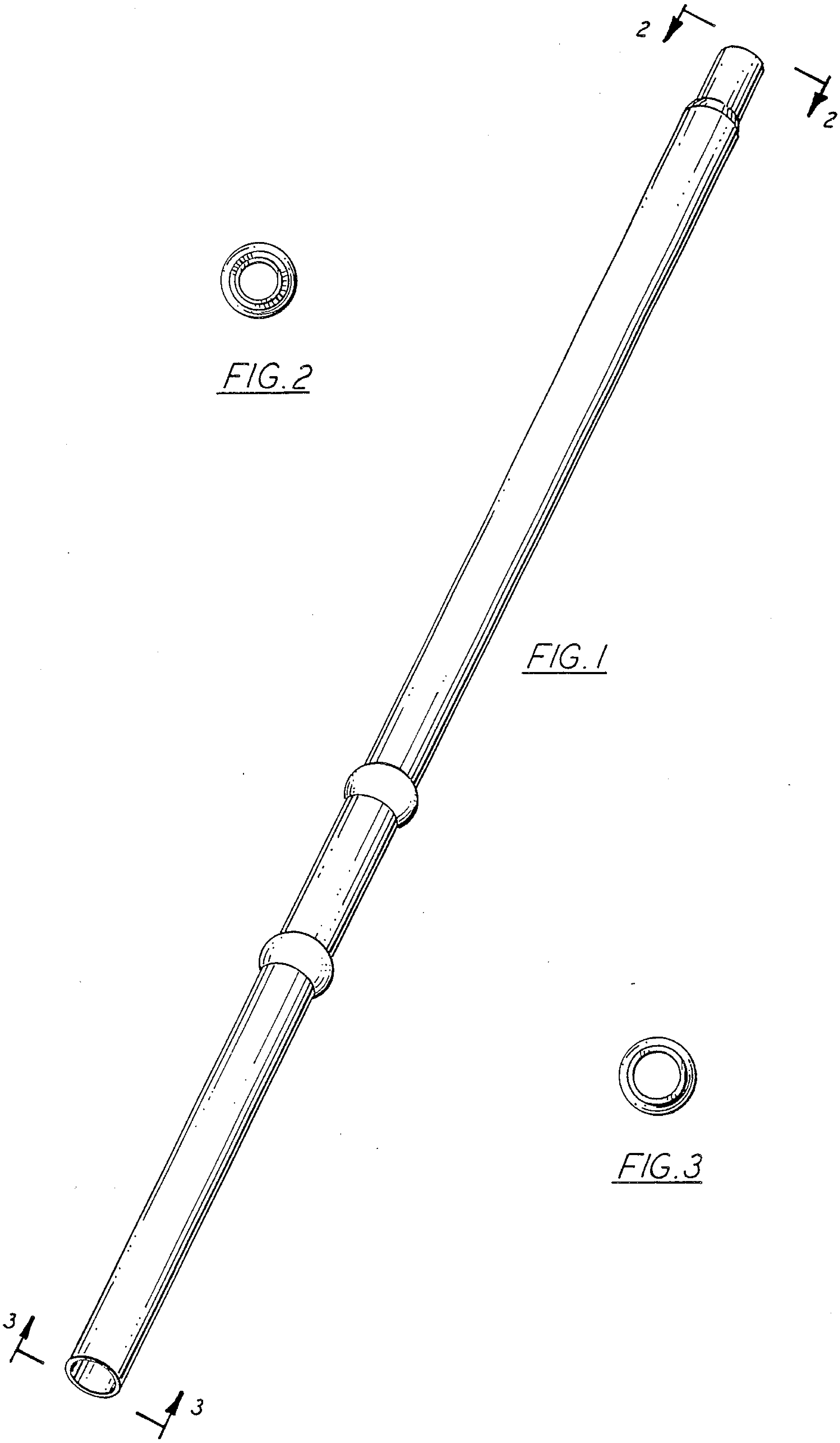


FIG. 1

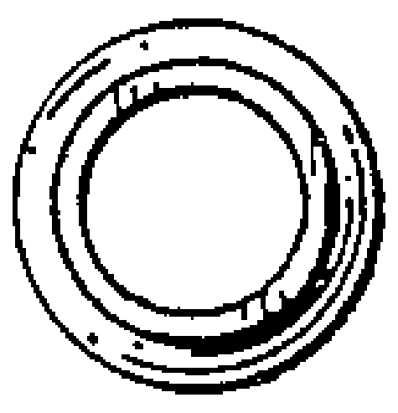


FIG. 3